

<b>Notice of References Cited</b>	Application/Control No. 10/696,431	Applicant(s)/Patent Under Reexamination HAN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,071,868	01-1978	Kaminaka et al.	360/319
*	B	US-6,166,487	12-2000	Negishi et al.	313/495
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05266434 A	10-1993	Japan	HAMAKAWA et al.	
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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